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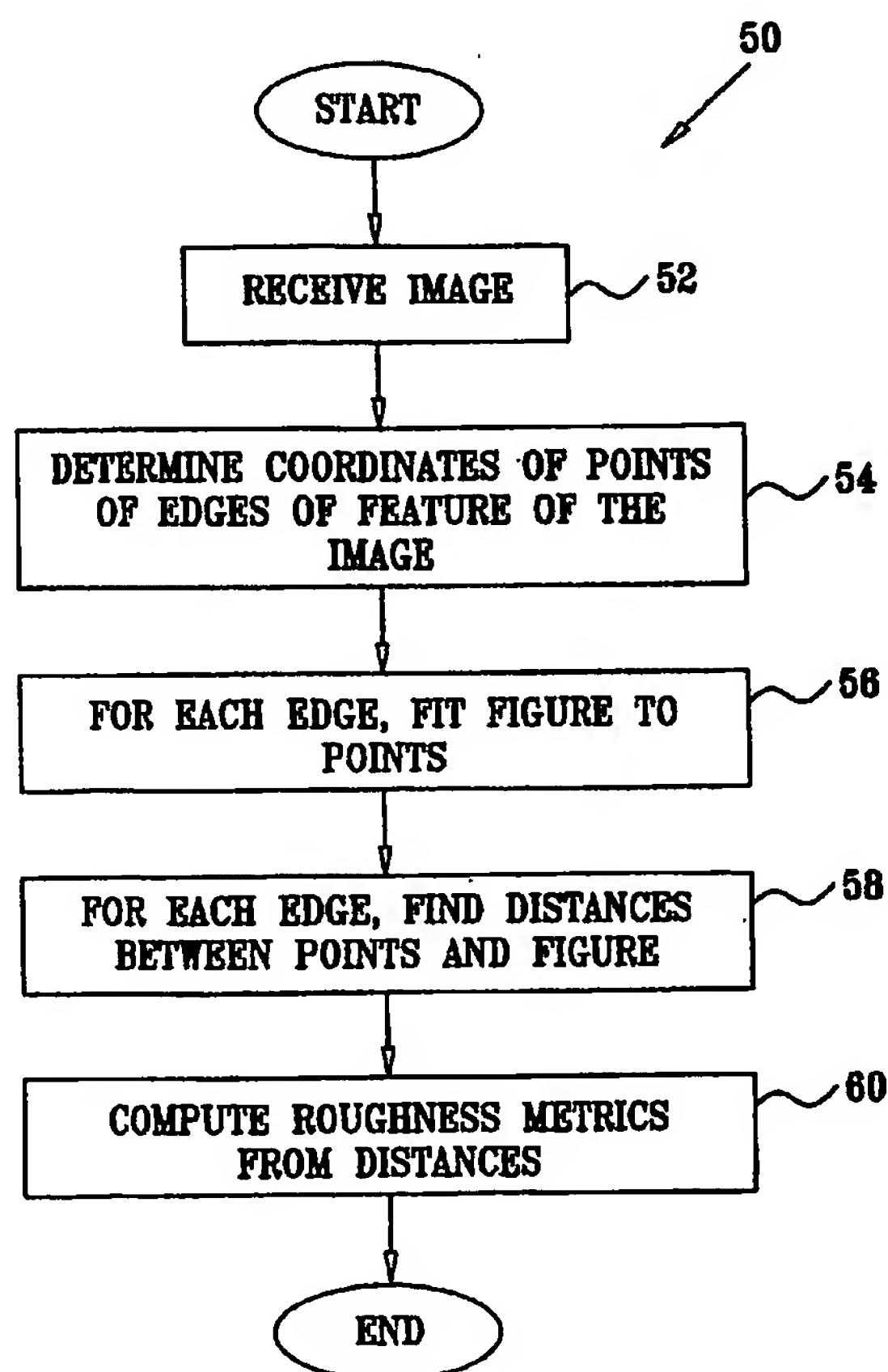
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(54) Title: **ADVANCED ROUGHNESS METROLOGY**



(57) Abstract: A method for evaluating a feature, consisting of re-
ceiving an image of the feature and determining respective coordi-
nates of a plurality of points on an edge of the feature in the image. A
figure having a non-circular non-linear shape is fitted to the plural-
ity of points, and respective distances between the plurality of points
and the figure are determined. A roughness parameter for the fea-
ture is computed in response to the respective distances. The method
finds application in the analysis of critical dimensions (CD) of in-
tegrated circuits and, particularly, in the measurement of the edge
roughness of their features and components as imaged by means of
eg. The electron scanning microscopy (SEM).



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